

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination	
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	Examiner Phallaka Kik	Art Unit 2825	Page 1 of 3

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		Examiner Phallaka Kik	Art Unit 2825	Page 2 of 3

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Examiner		Art Unit	Phallaka Kik	
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